Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/004,019	TOH ET AL.
Examiner	Art Unit
Shin-Hon Chen	2131

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT, PGPUB, JPO, EPO, DERWENT (BRS Search)	6/21/2006	S.C.	